



Item	Part Number	Description	QTY	UOM	List Price	Offered Price
		MODEL, SP2	1			
		Lead time 35 weeks ARO				
		Surfscan SP2 Wafer Surface Inspection System	1			
		Provide the following benefits:				
		*Optimized sensitivity and throughput - < 37nm defect sensitivity on polished bare silicon				
		*Enables qualification of current and next-generation substrates, SOI, strained SOI and strained Si				
		*Qualification and monitoring of process tools, at the 90, 65 and 45 nm technology nodes				
		*Assists in process troubleshooting and development				
		Includes the following components:				
		*UV laser				
		*Defect map and histogram with zoom				
		*iMicroView measurement capability				
		*SURFimage				
		*Real-Time Defect Classification (RTDC)				
		*Microsoft Windows XP Operating System				
		Features the following inspection modes:	1			
		* Standard Throughput Inspection Mode				
		* High Sensitivity Inspection Mode				
		Advanced Illumination Optics supporting the following mode(s):	1			
		* Oblique Illumination				
		Equipped with Powder Coat Painted Panels	1			
		Includes 300mm Phoenix Dual FIMS Vacuum Wafer Handler (PP)	1			
		*Ballroom Configuration (Standard)	1			
		Configured for ELB (ASIA) Power Inlet	1			
		Includes the following enable licenses:	1			
		*Optical Filter				
		*Enhanced XY Coordinates				
		*2mm Edge Exclusion				
		*Standard Classification Package				
		*LPD-N Classification				
		*LPD-ES Classification				
		*Grading and Sorting				
		*Haze				
		*Haze Analysis and Normalization				
		*Haze Line Classification				
		*IDM				
		Configured for IC/OEM Mfg Surf Quality Recipe	1			
		Crate, STD Shipping, SP2	1			
		Sag Protection, F47, 208V	1			
		Oblique Incidence	1			

